

Strips: p+ implant responsible for charge multiplication covers only part of the strip.

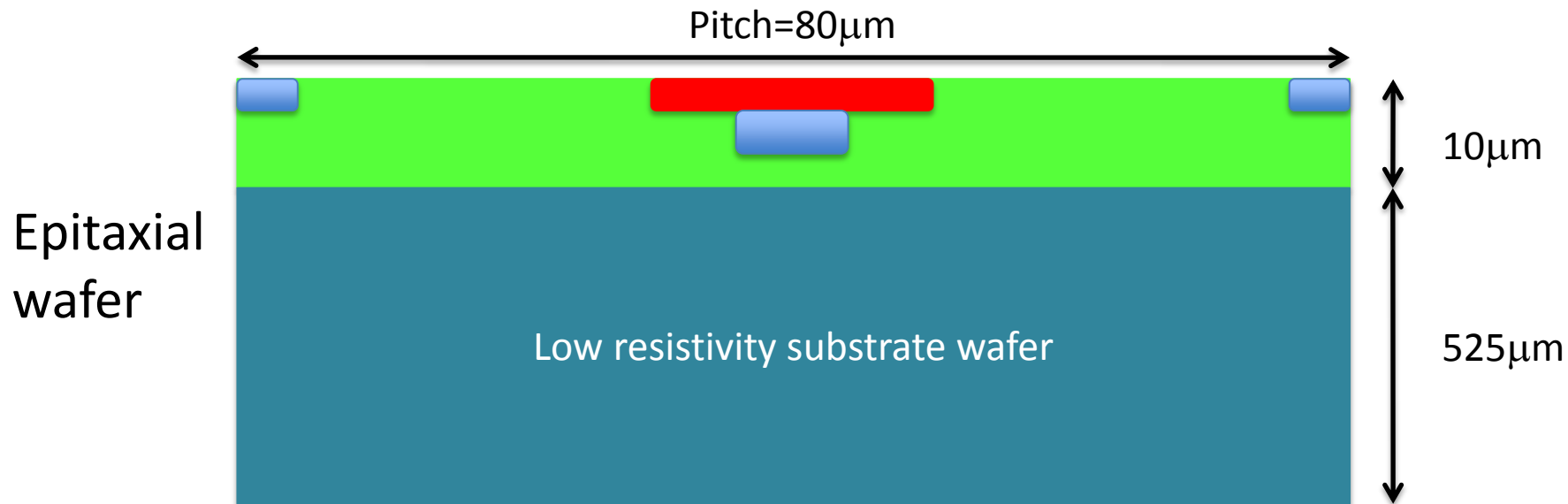
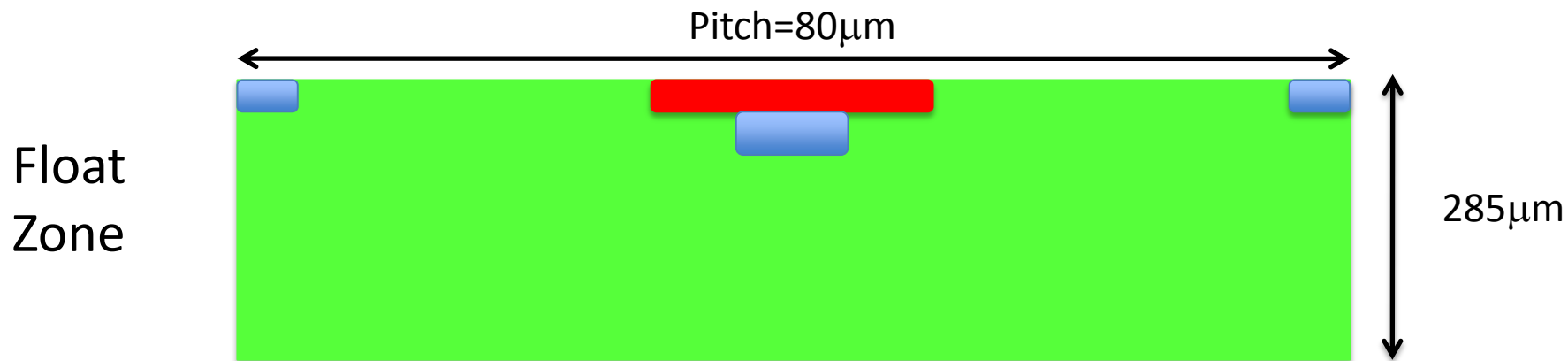
Investigate extension of p+ to cover the entire sensor and topush it deeper into the bulk

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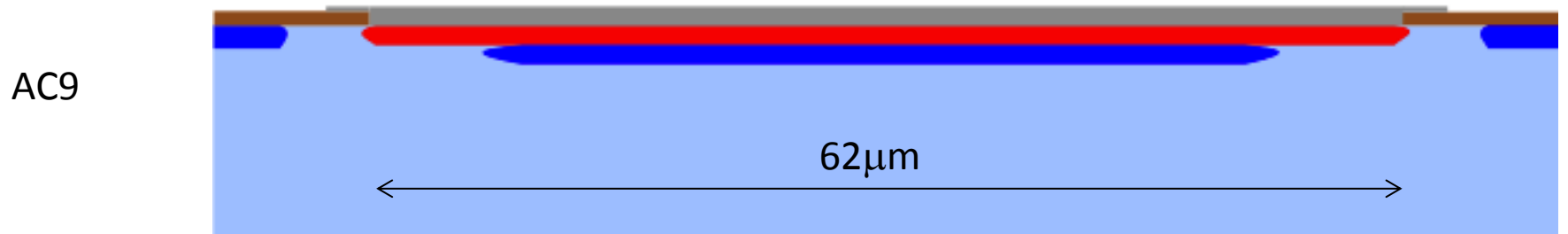
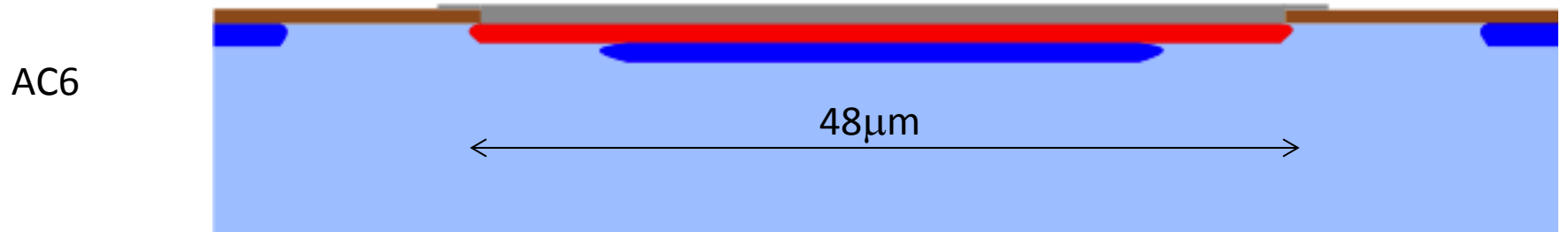
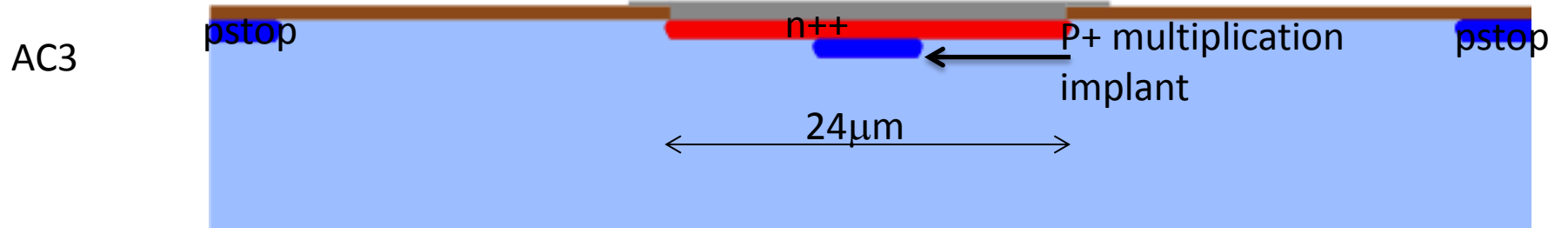
Strip detectors

Pitch $p=80\ \mu\text{m}$

	Strip w [μm]	Metal [μm]	P-implant [μm]	w/p	P-implant/pitch
AC1	24	20	6	0.3	7.5%
AC2	24	24	6	0.3	7.5%
AC3	24	28	6	0.3	7.5%
AC4	48	44	30	0.6	37.5%
AC5	48	48	30	0.6	37.5%
AC6	48	52	30	0.6	37.5%
AC7	62	58	44	0.775	55%
AC8	62	62	44	0.775	55%
AC9	62	66	44	0.775	55%
AC10/AC11/ DC	32	40	14	0.4	17.5%

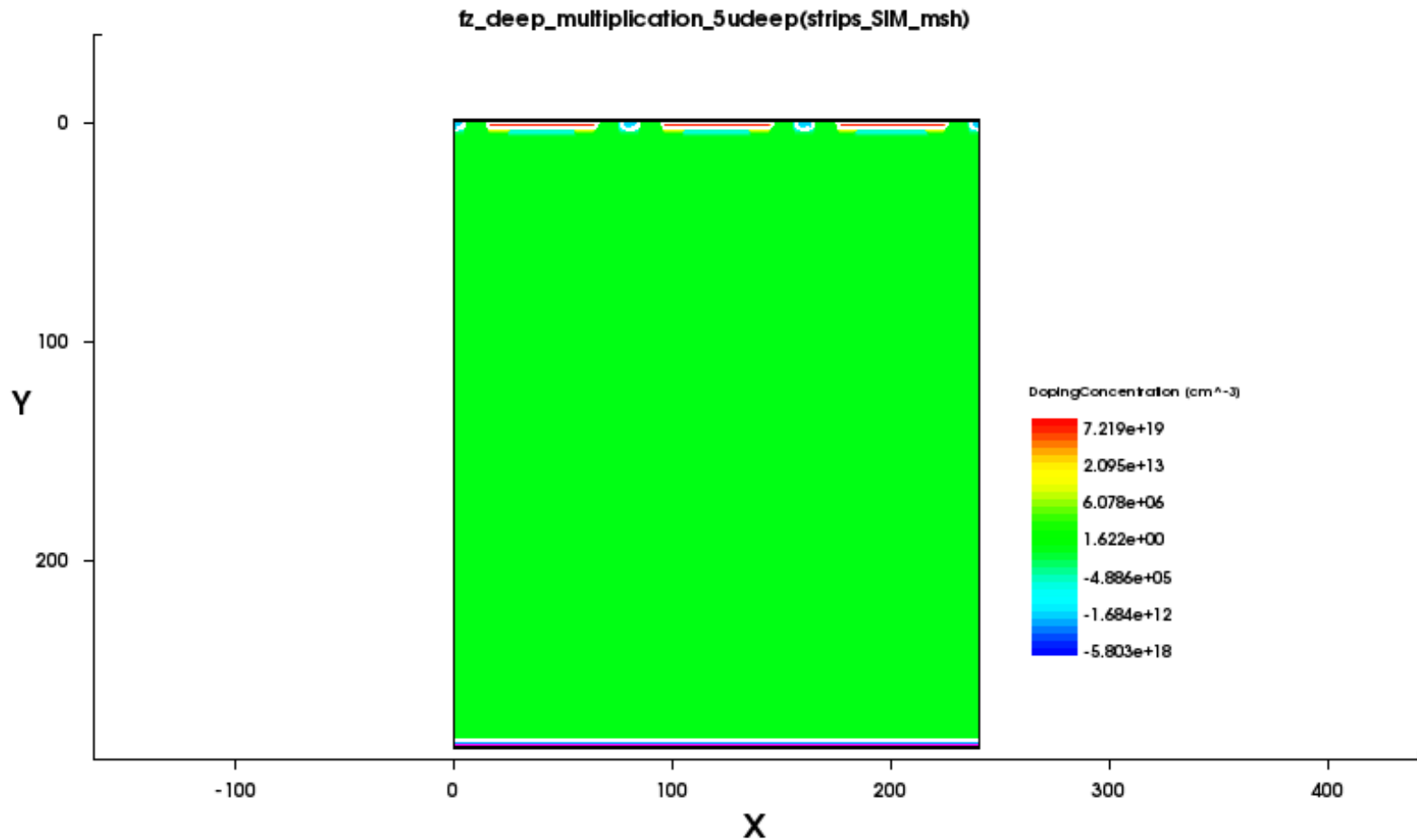


Pitch 80μm

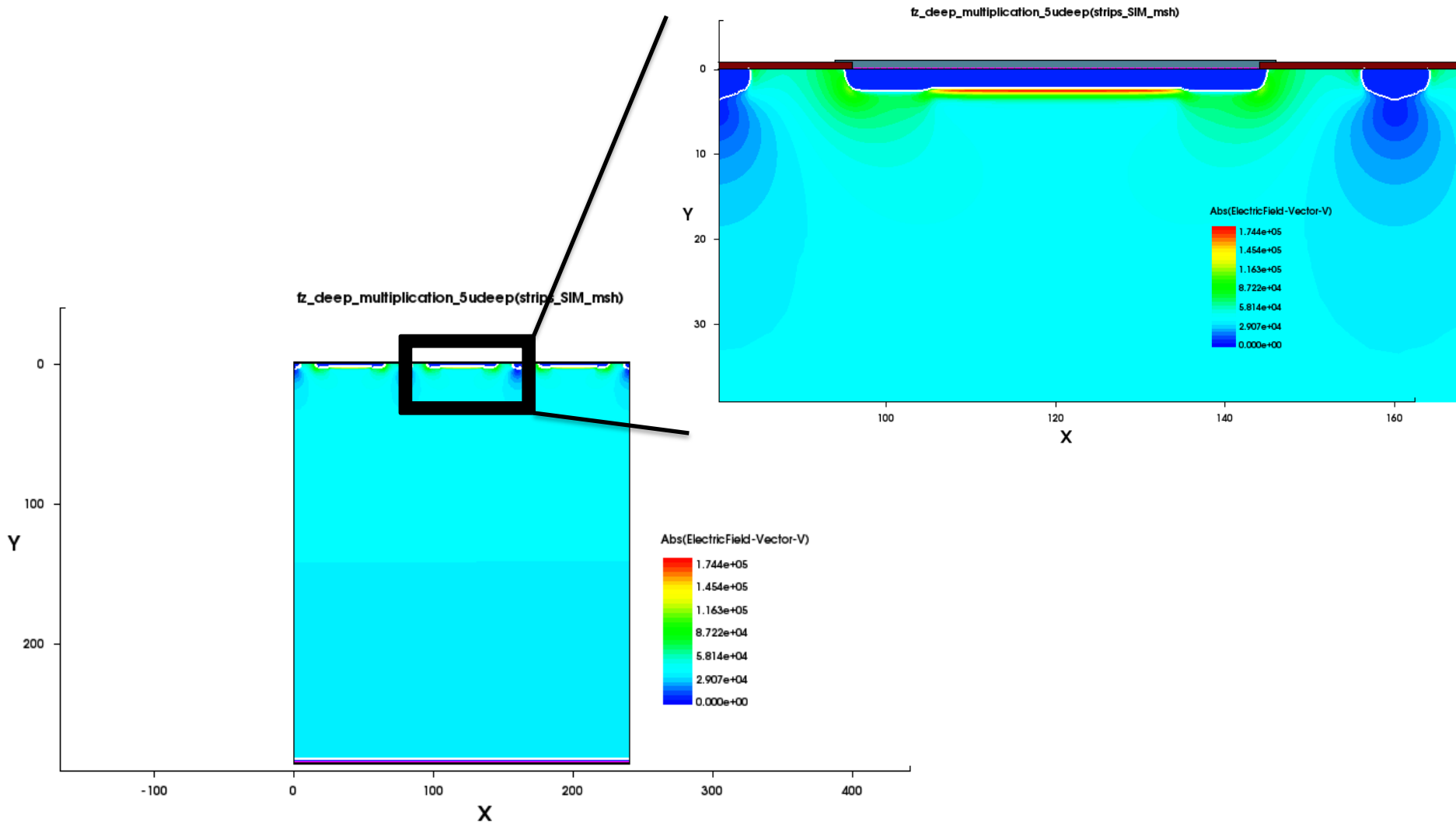


REGULAR STRIPS AC6

Regular Strips (AC 6 FZ Deep annealing)

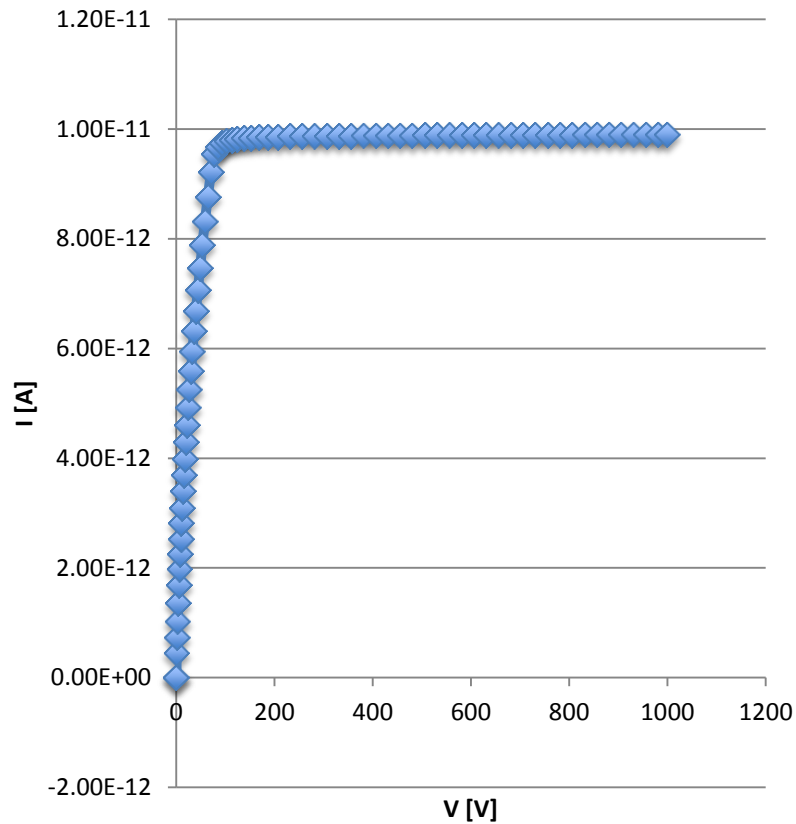


Electric field of regular strips @1000V (AC 6 FZ Deep annealing)

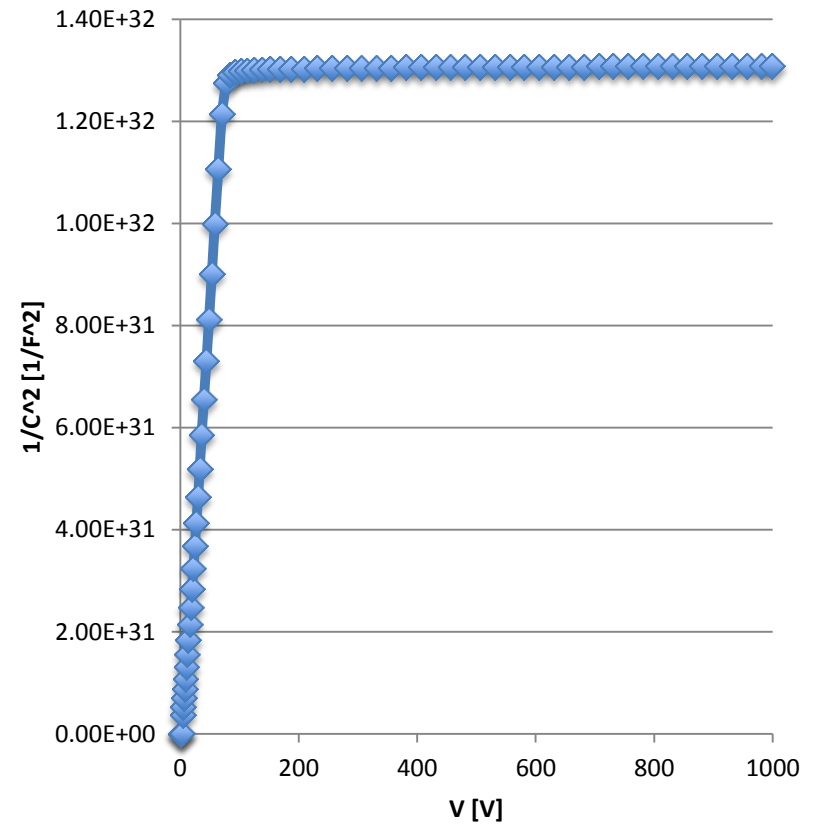


IV and CV for regular strips (AC 6 FZ Deep annealing)

IV regular strip



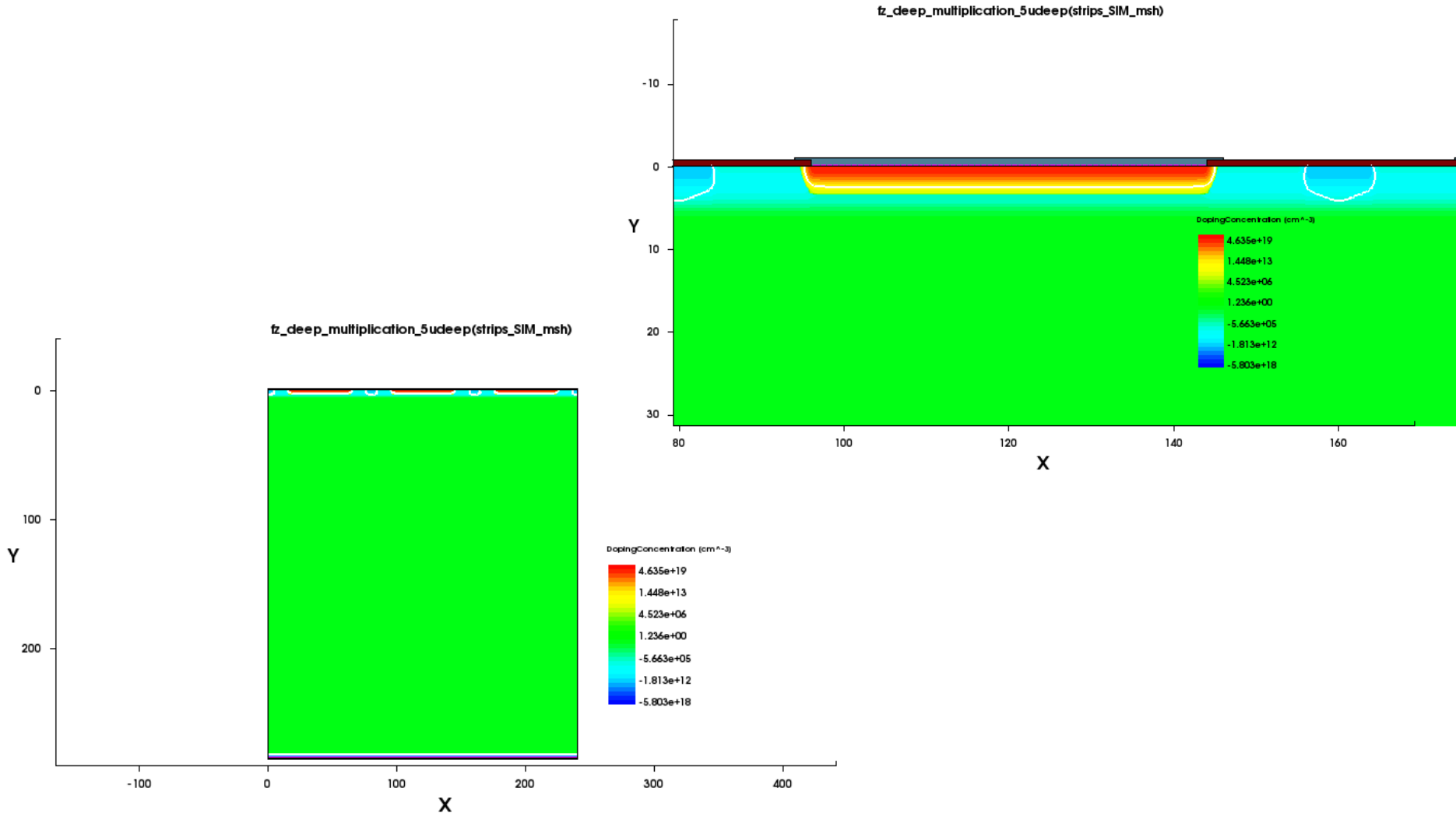
CV regular strip



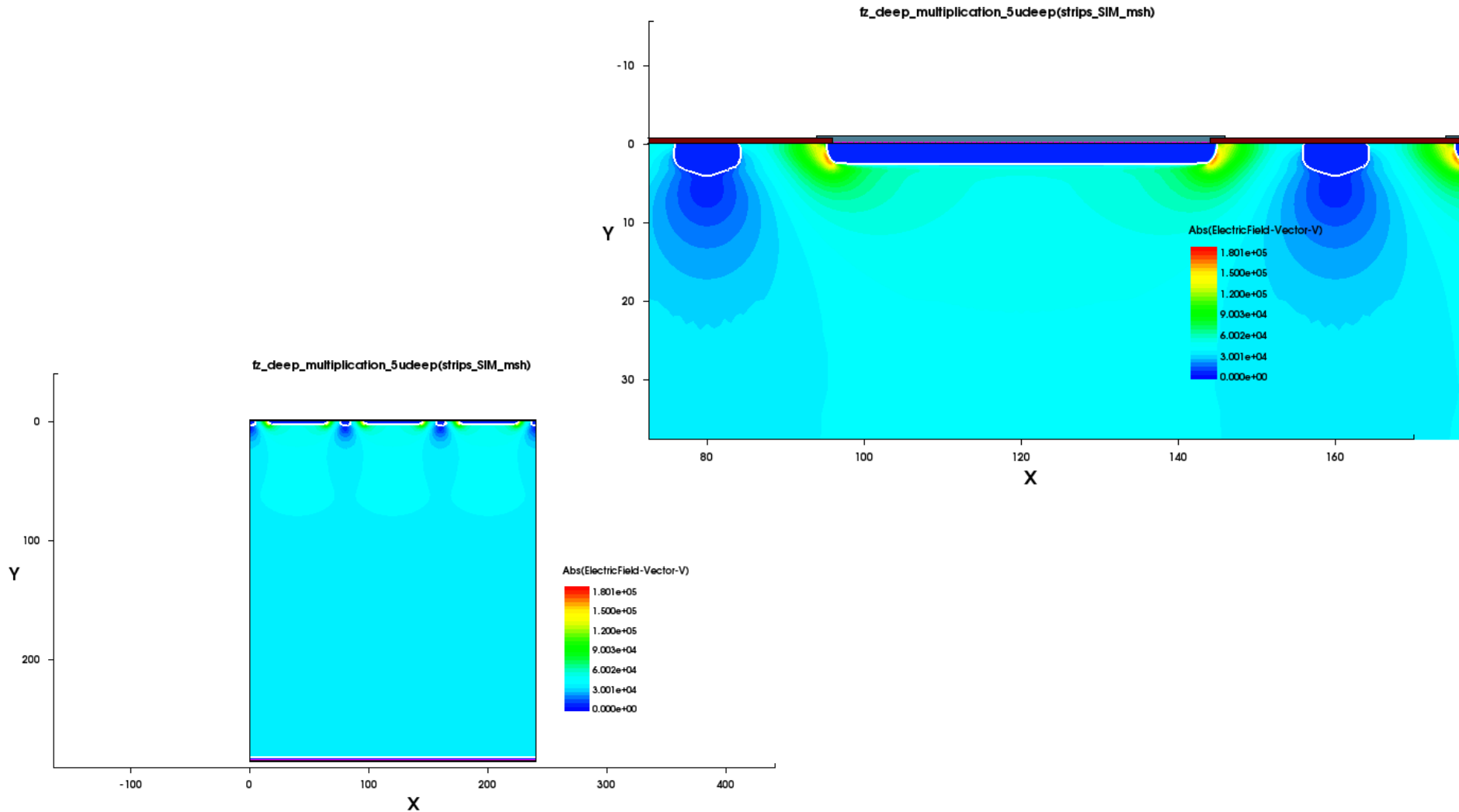
NEW STRIPS

Doping boron peak $1e15\text{cm}^{-3}$ boron
at $2\mu\text{m}$

New strips (boron at 2um from the surface) doping boron $1e15\text{cm}^{-3}$

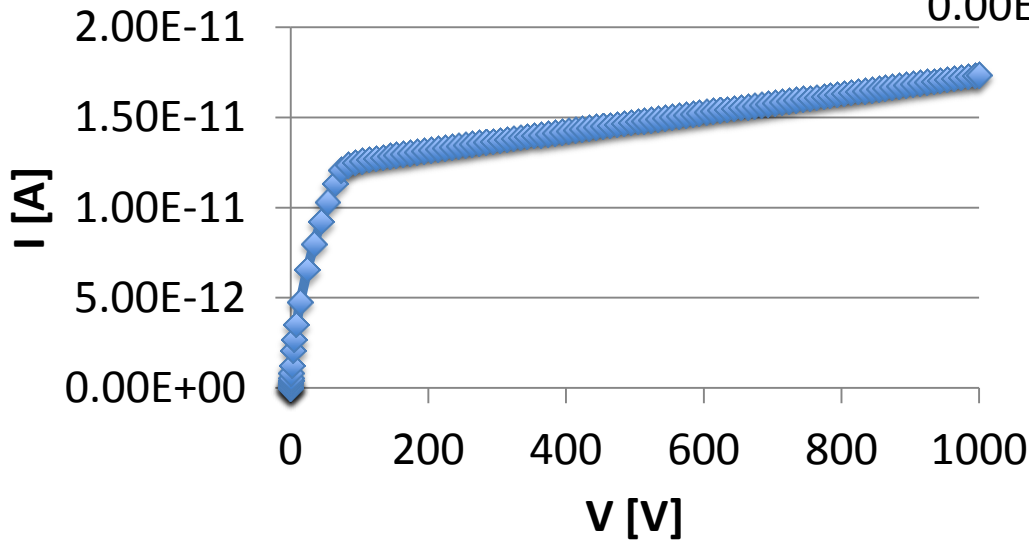


New strips electric field @1000V doping boron $1e15\text{cm}^{-3}$ @2um

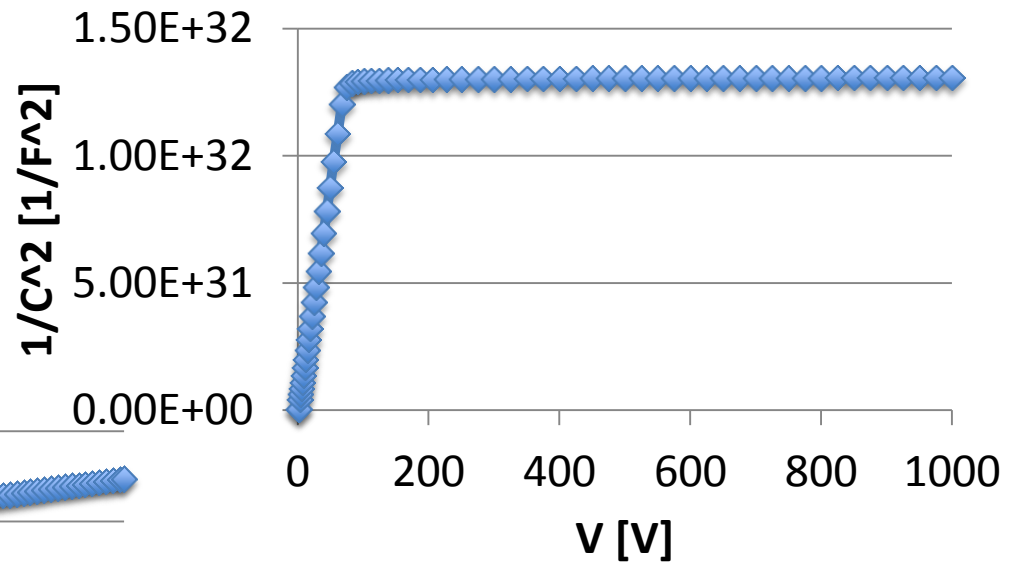


IV and CV for strips with boron @ 2um boron doping $1e15\text{cm}^{-3}$

IV boron $1e15@2\mu\text{m}$ deep



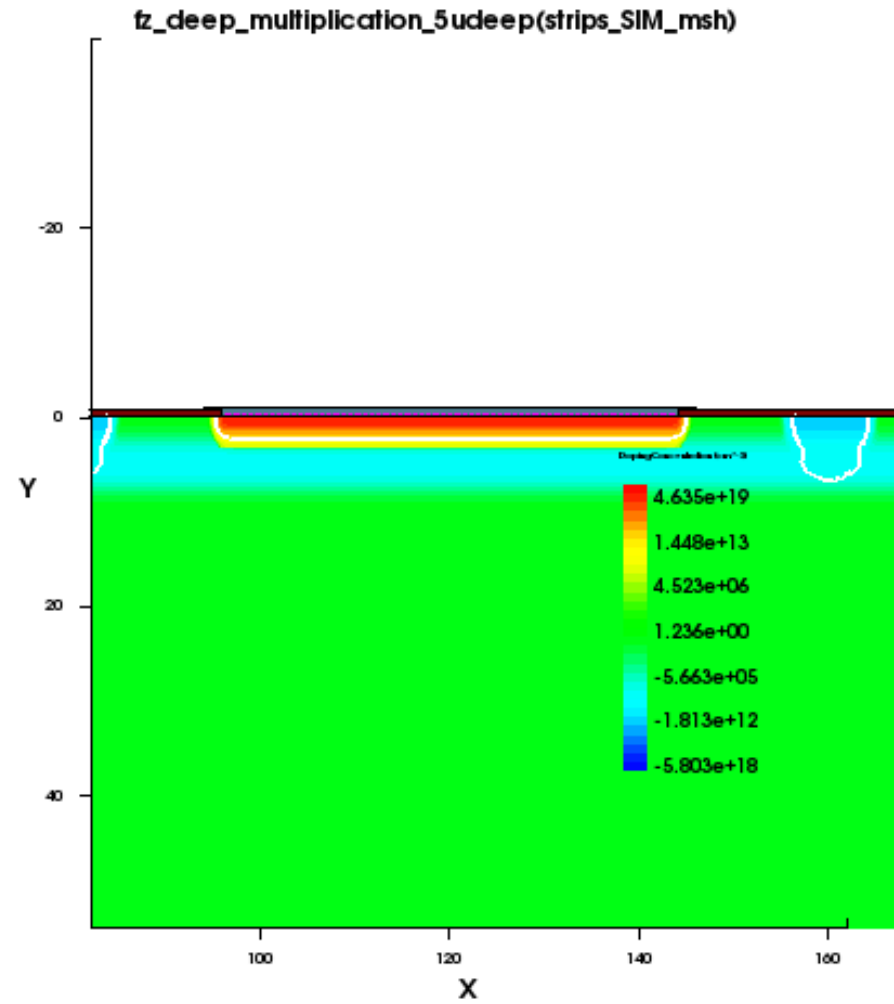
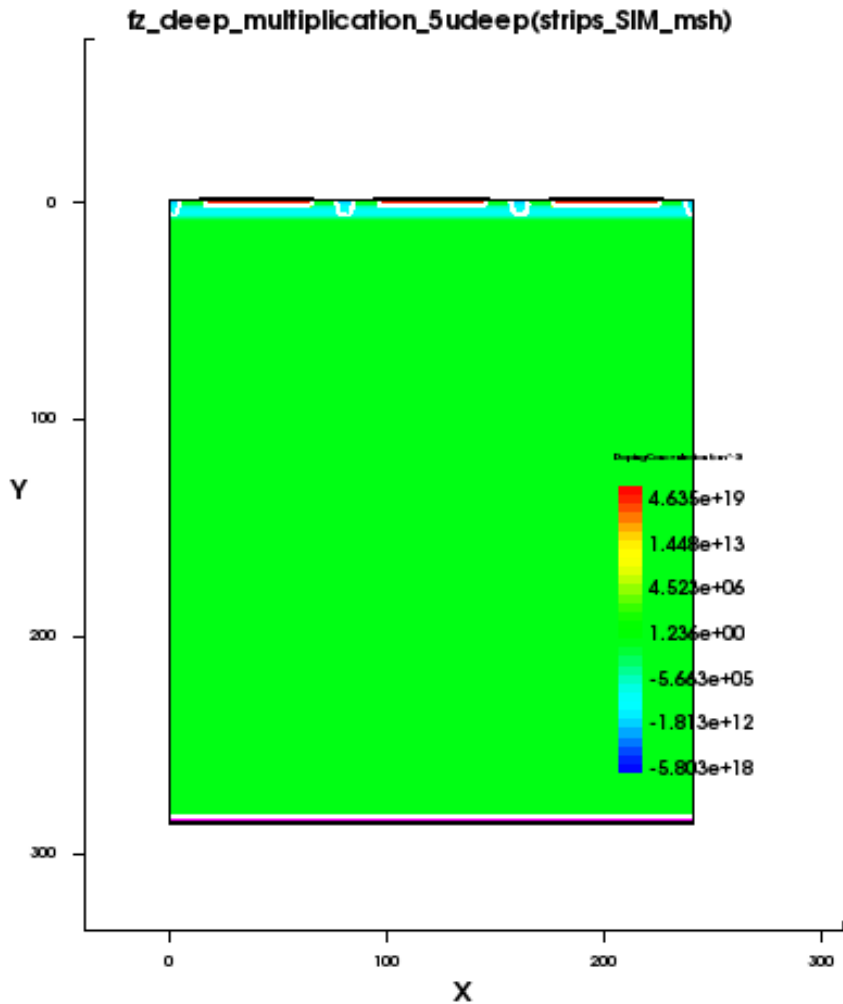
CV boron $1e15 @ 2\mu\text{m}$ deep



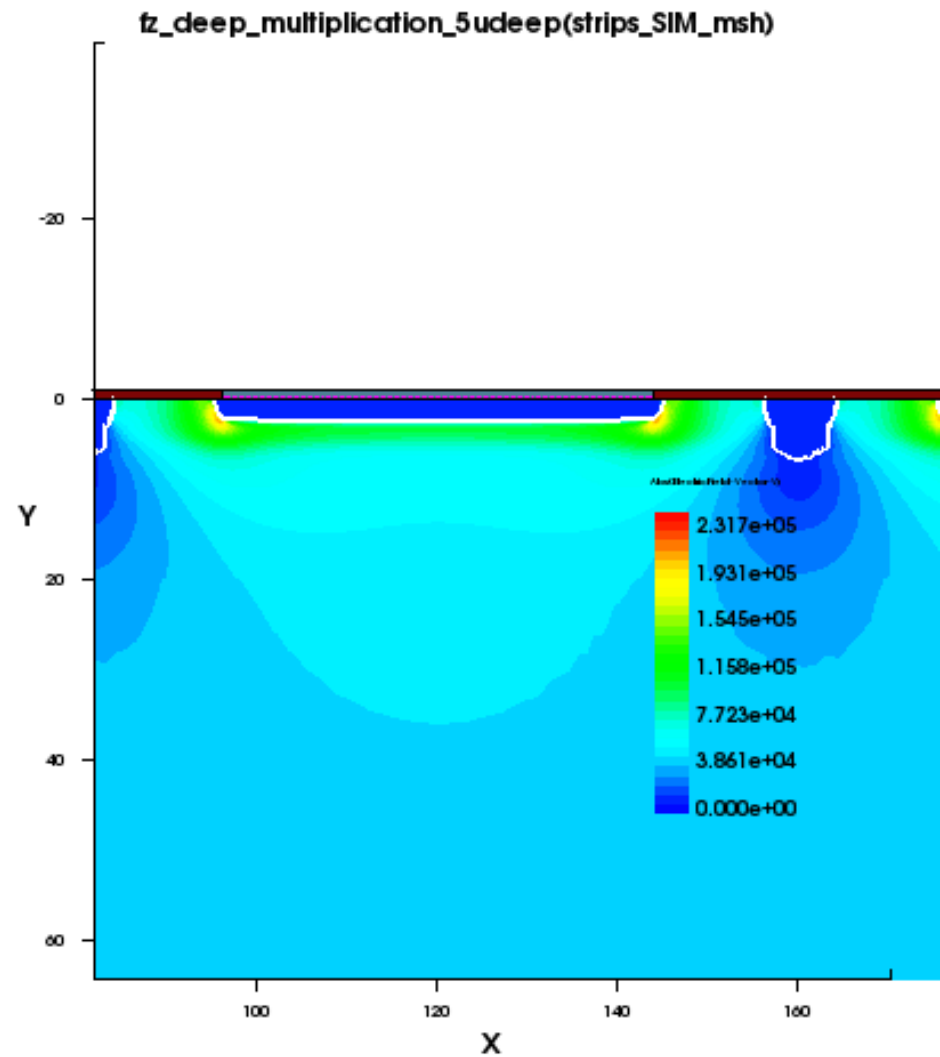
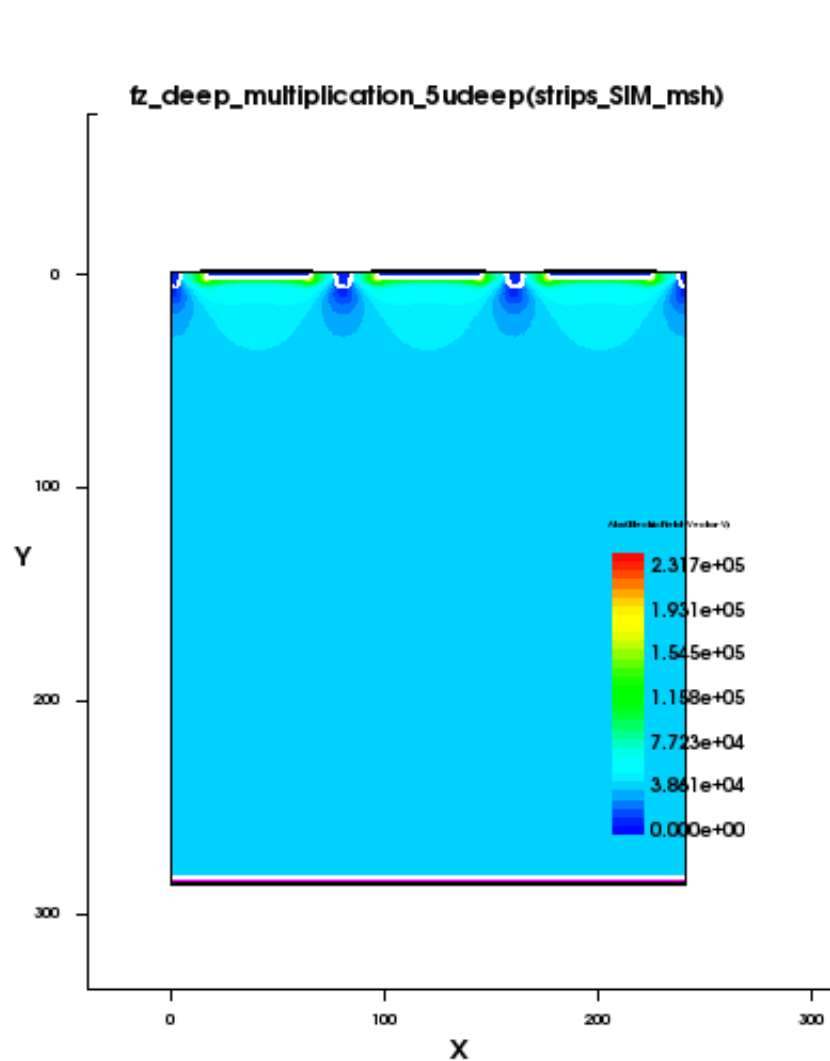
NEW STRIPS

Doping boron peak $1e15\text{cm}^{-3}$ at
5um deep

New strips (boron at 5um from the surface) doping boron $1e15\text{cm}^{-3}$

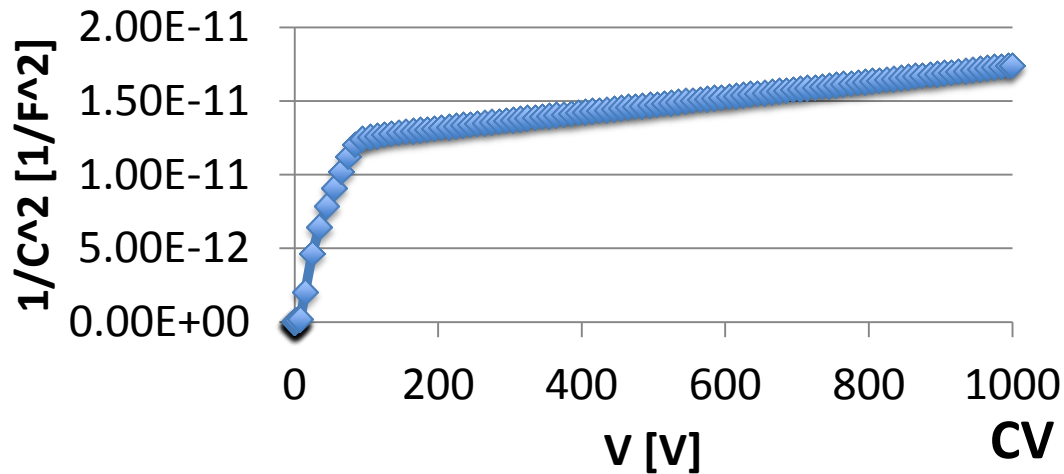


New strips electric field @1000V doping boron $1e15\text{cm}^{-3}$



IV and CV for strips with boron @ 5um boron doping $1e15\text{cm}^{-3}$

IV boron doses $1e15\text{cm}^{-3}$



CV boron dose $1e15\text{cm}^{-3}$

